



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 10/720,123
Filing Date: November 25, 2003
Applicant: Hoi-Jin Lee
Group Art Unit: 2138
Examiner: John P. Trimmings
Title: SEMICONDUCTOR DEVICE WITH SPEED BINNING TEST CIRCUIT AND
TEST METHOD THEREOF
Attorney Docket: 2557-000191/US

Customer Service Window
Randolph Building
401 Dulany Street
Alexandria, VA 22314
Mail Stop Amendment

July 3, 2006

AMENDMENT

Sir:

In response to the non-final Office Action mailed April 3, 2006, the following amendments and remarks are respectfully submitted in connection with the above-identified application.

Amendments to the Specification begin on page 2 of this Amendment.

Amendments to the Claims begin on page 3 of this Amendment.

Amendments to the Drawings begin on page __ of this Amendment.

Remarks begin on page 7 of this Amendment.

	Claims remaining after Amendment		Highest number previously paid for		Present extra
Total	22	-	25	=	0
Independent	3	-	3	=	0